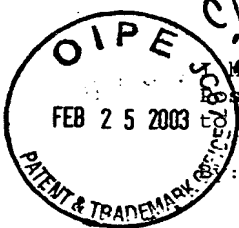


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I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage, as first class mail in an envelope addressed to the Assistant Commissioner for Patents, Washington, D.C. 20231

Date: February 20, 2003

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Michael Schittenhelm
Applic. No. : 09/992,290
Filed : November 16, 2001
Title : Method of Calibrating a Test System for
Semiconductor Components, and Test Substrate
Examiner : Tung X. Nguyen
Group Art Unit : 2829

A M E N D M E N T

Hon. Commissioner of Patents and Trademarks,
Washington, D. C. 20231

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S i r :

Responsive to the Office action dated November 20, 2002 kindly
amend the above-identified application as follows:

In the Claims:

a'
Claim 1(amended). A calibration method for a test system
wherein semiconductor components are tested by making contact
with a component to be tested via a probe card, the method
which comprises: